

# Construction of mixed-dimensional WS<sub>2</sub>/Si heterojunctions for high-performance infrared photodetection and imaging applications

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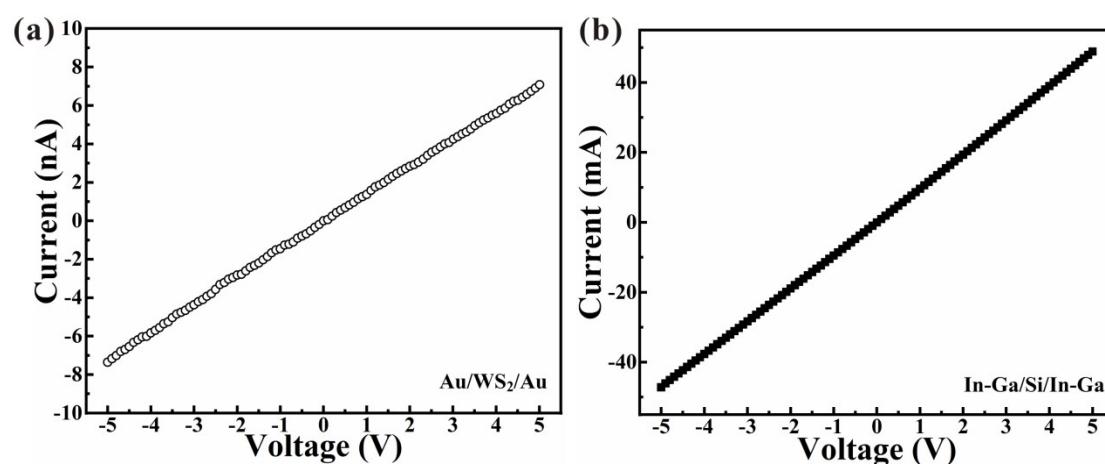


Fig. S1 I-V curves of (a) Au/WS<sub>2</sub>/Au and (b) In-Ga/Si/In-Ga.

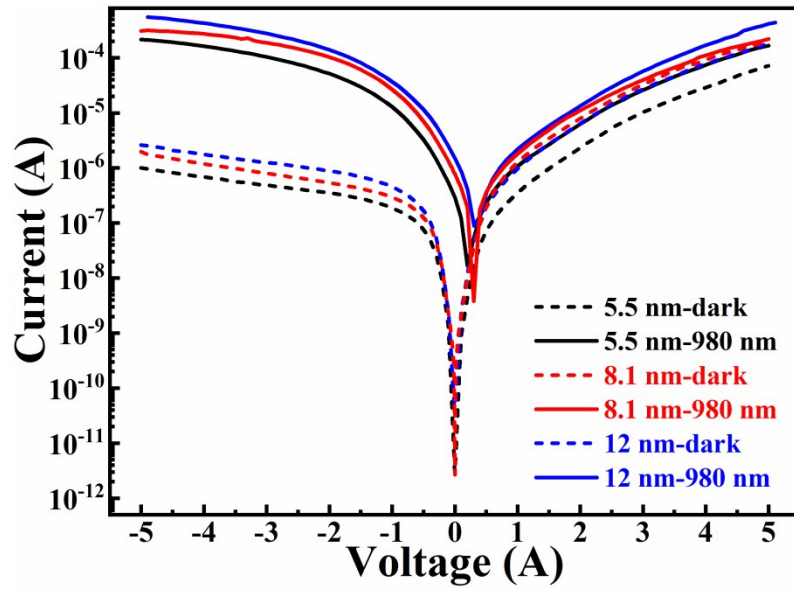


Fig. S2 I-V curves of  $\text{WS}_2/\text{Si}$  heterojunction devices with  $\text{WS}_2$  thickness of 5.5, 8.1 and 12 nm in dark and under 980 nm.

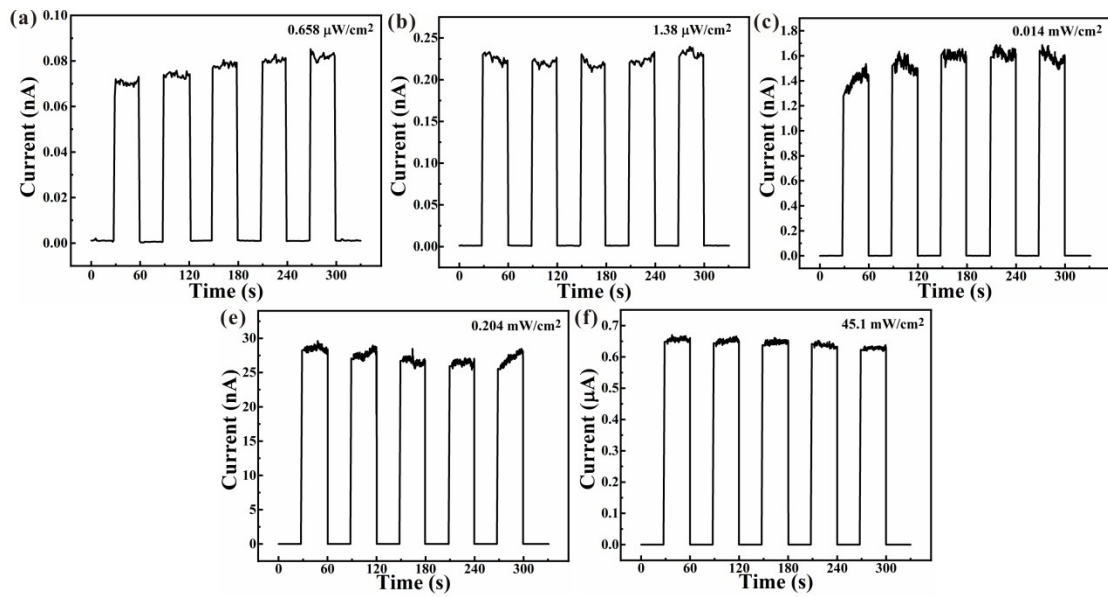


Fig. S3 Time-dependent photoresponse of the  $\text{WS}_2/\text{Si}$  heterojunction under 980 nm light with varying light intensities in linear scale.

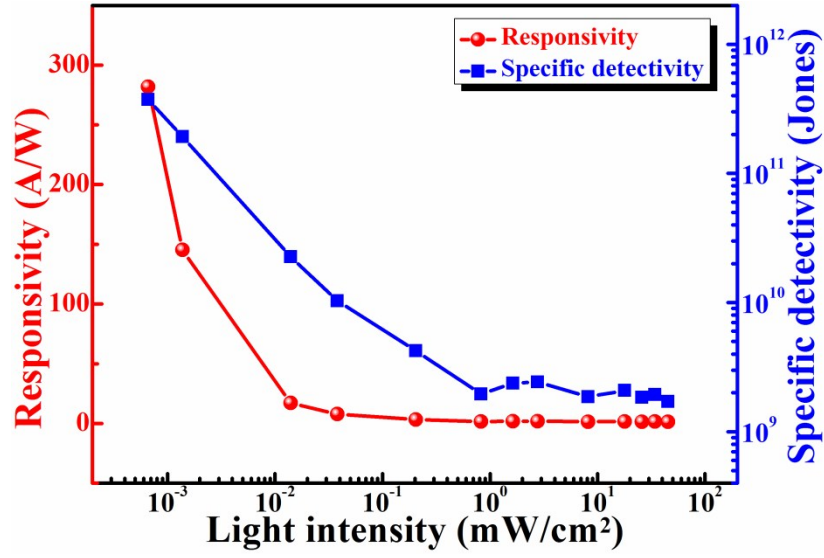


Fig. S4 Responsivity and specific detectivity of the WS<sub>2</sub>/Si heterojunction at a voltage bias of -5 V.

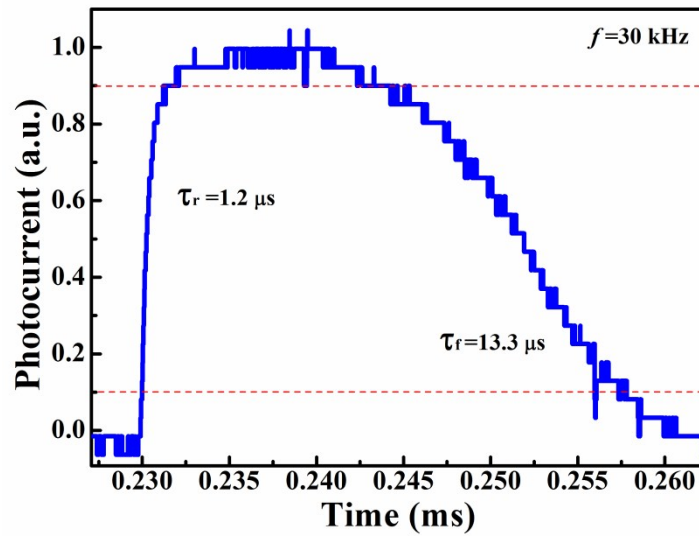


Fig. S5 Response speeds of the WS<sub>2</sub>/Si heterojunction at a frequency of 30 kHz.